



# P-Channel Enhancement-Mode Vertical DMOS FETs

### **Ordering Information**

BV <sub>DSS</sub> /	R <sub>DS(ON)</sub>	I <sub>D(ON)</sub>	V <sub>GS(th)</sub>	Order Number / Package		
BV <sub>DGS</sub>	(max)	(min)	- ,	TO-92		
-200V	12Ω	-0.75A	-2.4V	TP0620N3		

<sup>†</sup> MIL visual screening available

#### **Features**

- ☐ Low threshold -2.4 V max
- ☐ High input impedance
- Low input capacitance 85pF typical
- Fast switching speeds
- Low on resistance
- Free from secondary breakdown
- Low input and output leakage
- Complementary N- and P-channel devices

### **Applications**

- Logic level interfaces ideal for TTL and CMOS
- Solid state relays
- Battery operated systems
- Photo voltaic drives
- Analog switches
- General purpose line drivers
- ☐ Telecom switches

### **Absolute Maximum Ratings**

Drain-to-Source Voltage	$BV_{DSS}$
Drain-to-Gate Voltage	BV <sub>DGS</sub>
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

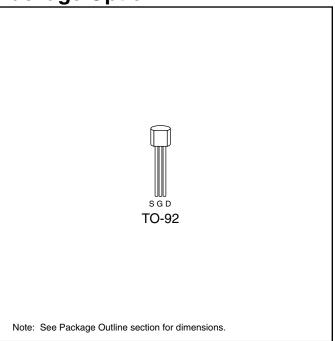
<sup>\*</sup> Distance of 1.6 mm from case for 10 seconds.

# **Low Threshold DMOS Technology**

These low threshold enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

### **Package Option**



### **Thermal Characteristics**

Package	I <sub>D</sub> (continuous)*	I <sub>D</sub> (pulsed)	Power Dissipation @ T <sub>C</sub> = 25°C	$ heta_{ extsf{jc}}$ $^{\circ}$ C/W	$ heta_{ja}$ °C/W	I <sub>DR</sub> *	I <sub>DRM</sub>
TO-92	-175mA	-0.8A	1W	125	170	-175mA	-0.8A

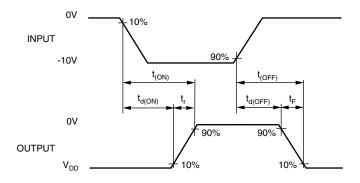
<sup>\*</sup> I<sub>D</sub> (continuous) is limited by max rated T<sub>j</sub>.

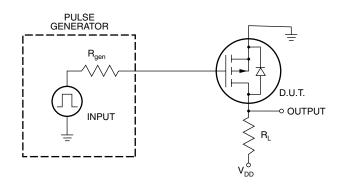
# Electrical Characteristics (@ 25°C unless otherwise specified)

Symbol	Parameter	Min	Тур	Max	Unit	Conditions	
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	-200			V	$V_{GS} = 0V$ , $I_D = -2.0$ mA	
V <sub>GS(th)</sub>	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}$ , $I_D = -1.0$ mA	
$\Delta V_{GS(th)}$	Change in V <sub>GS(th)</sub> with Temperature			-4.5	mV/°C	$V_{GS} = V_{DS}$ , $I_D = -1.0 \text{mA}$	
I <sub>GSS</sub>	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20V$ , $V_{DS} = 0V$	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current			-10	μΑ	$V_{GS} = 0V$ , $V_{DS} = Max$ Rating	
				-1.0	mA	$V_{GS} = 0V$ , $V_{DS} = 0.8$ Max Rating $T_A = 125$ °C	
I <sub>D(ON)</sub>	ON-State Drain Current	-0.25			Α	$V_{GS} = -5V, V_{DS} = -25V$	
		-0.75			A	$V_{GS} = -10V, V_{DS} = -25V$	
R <sub>DS(ON)</sub>	Static Drain-to-Source ON-State Resistance		9.0	15	Ω	$V_{GS} = -5V, I_D = -0.1A$	
			7.0	12		$V_{GS} = -10V, I_D = -0.2A$	
$\Delta R_{DS(ON)}$	Change in R <sub>DS(ON)</sub> with Temperature			1.7	%/°C	$V_{GS} = -10V, I_D = -0.2A$	
G <sub>FS</sub>	Forward Transconductance	100	150		m&	$V_{DS} = -25V, I_{D} = -0.4A$	
C <sub>ISS</sub>	Input Capacitance		85	150		$V_{GS} = 0V, V_{DS} = -25V$	
C <sub>oss</sub>	Common Source Output Capacitance		30	85	pF	f = 1 MHz	
C <sub>RSS</sub>	Reverse Transfer Capacitance		10	35			
t <sub>d(ON)</sub>	Turn-ON Delay Time			10		V <sub>DD</sub> = -25V	
t <sub>r</sub>	Rise Time			15	ns	$I_D = -0.75A$ $R_{GEN} = 25\Omega$	
t <sub>d(OFF)</sub>	Turn-OFF Delay Time			20			
t <sub>f</sub>	Fall Time			16			
V <sub>SD</sub>	Diode Forward Voltage Drop			-1.8	V	$V_{GS} = 0V, I_{SD} = -0.5A$	
t <sub>rr</sub>	Reverse Recovery Time		300		ns	$V_{GS} = 0V, I_{SD} = -0.5A$	

#### Notes:

# **Switching Waveforms and Test Circuit**

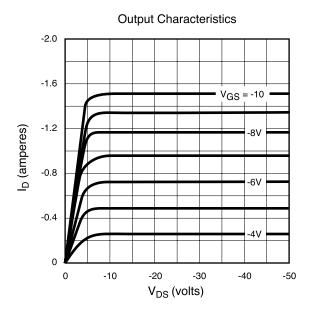




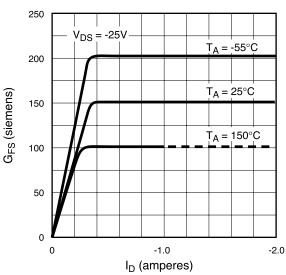
<sup>1.</sup> All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)

<sup>2.</sup> All A.C. parameters sample tested.

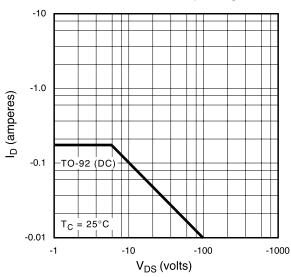
# **Typical Performance Curves**

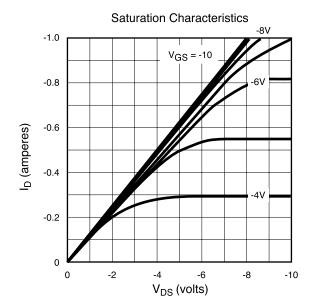


#### Transconductance vs. Drain Current

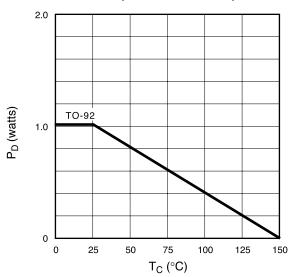


#### Maximum Rated Safe Operating Area

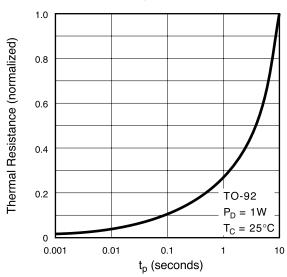




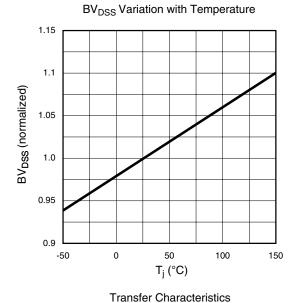
#### Power Dissipation vs. Case Temperature

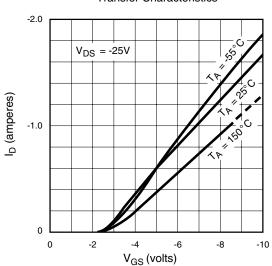


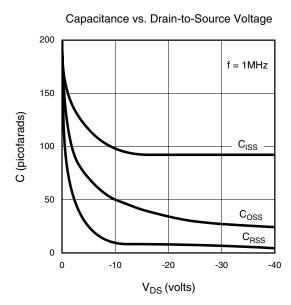
#### Thermal Response Characteristics

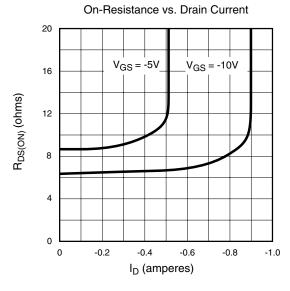


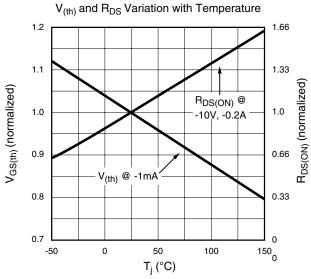
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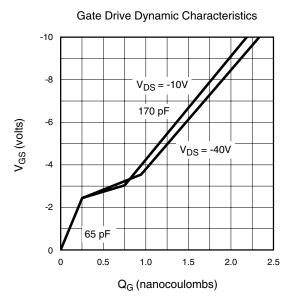












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